Nanolab Technologies Incorporated offers cutting edge technology and expertise for Failure Analysis, FIB Circuit Edit and Advanced Microscopy Services in support of the Semiconductor, MEMS, Materials Science and Nanotechnology Industries.

Comprised of an experienced Team of Analysts and an all new State-of-the-Art Laboratory equipped with Advanced Analytical Tools and Ultra High Resolution Instruments, Nanolab Technologies provides our customers solutions to the challenges of shrinking geometries, exotic materials and advanced processes.

- JEM-3010 300kV TEM
- Altura855 FIB/SEM
- Helios NanoLab400 FIB/SEM
- NanoSEM630 UHR SEM
- V600 FIB
- SOM 4000 EMMI/Laser
- 160.30 RTX
- H200 CSAM/3D
- HR Digital Microscopy
- TIC020 Ion Beam Cutter
- RES101 Rapid Etch
- 691 PIPS
- 692 PECS

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nanolab technologies

Our People Make the Difference

New State-of-the-Art Lab

Turnkey Failure Analysis (FA)

Competitive/Construction Analysis

Decap, Die Removal, Deprocessing, etc.

Emission Microscopy (EMMI)

FIB Circuit Edit (FIB)

DualBeam X Section Analysis (FIB/SEM)

Scanning Electron Microscopy (FESEM)

Transmission Electron Microscopy (TEM)

Energy Dispersive Spectroscopy (EDS)

Real Time X-Ray (RTX)

Scanning Acoustical Microscopy (CSAM)